

**Search Notes**

Application/Control No.

10/764,481

Examiner

MARK A. MAIS

Applicant(s)/Patent under  
Reexamination

HIYAMA ET AL.

Art Unit

2619

**SEARCHED**

| Class   | Subclass          | Date      | Examiner |
|---------|-------------------|-----------|----------|
| 370     | 310<br>328<br>329 | 6/16/2008 | MAM      |
|         | 331<br>338<br>351 |           |          |
|         | 352<br>353<br>389 |           |          |
|         | 392<br>401<br>469 |           |          |
|         | 474<br>475<br>476 |           |          |
| SAME AS | ABOVE             | 3/30/2008 | MAM      |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|   | DATE      | EXMR |
|---|-----------|------|
| See Inventorship Search                     | 6/16/2008 | MAM  |
| See Attached Electronic Search              | 6/16/2008 | MAM  |
| See Attached Electronic Search<br>[updated] | 3/30/2008 | MAM  |
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